

MTTS 2008 MicroApps

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# Accurate Phase Noise Measurements Made Cost Effective

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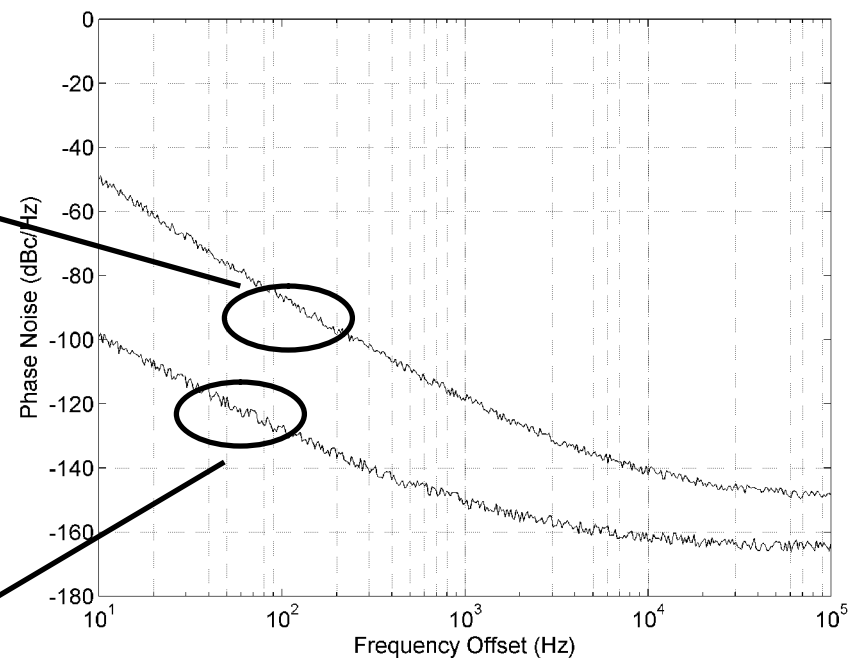
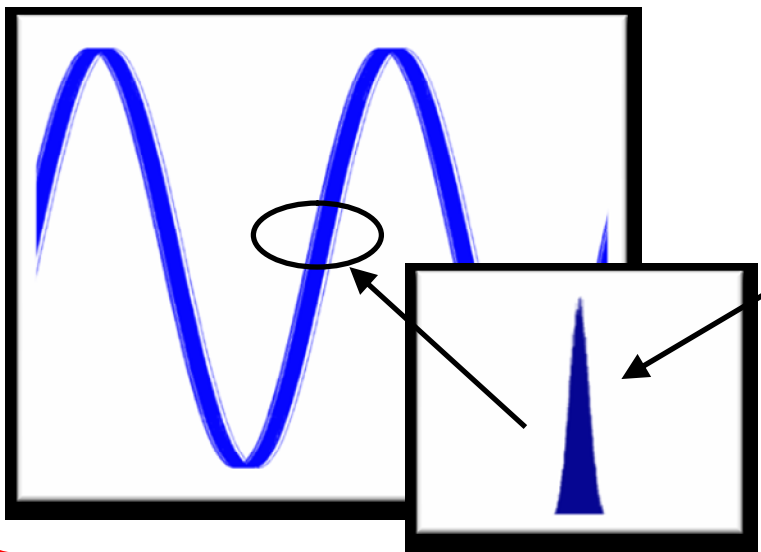
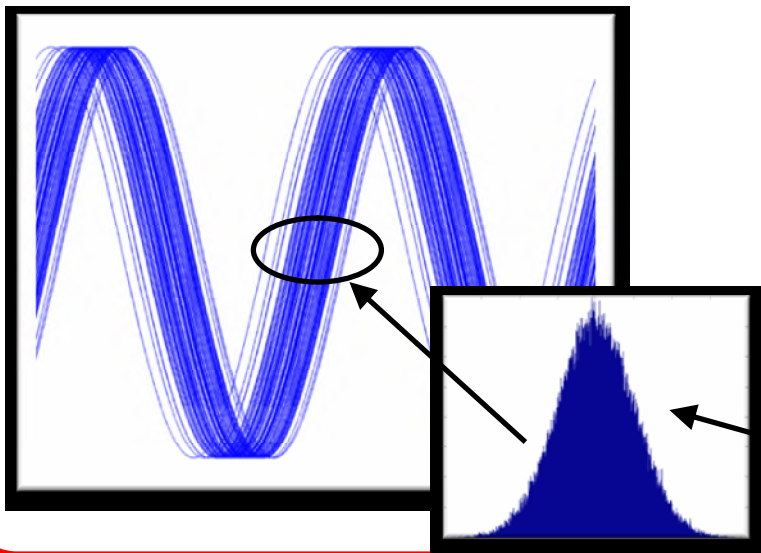
[www.holzworth.com](http://www.holzworth.com)

# Presentation Outline

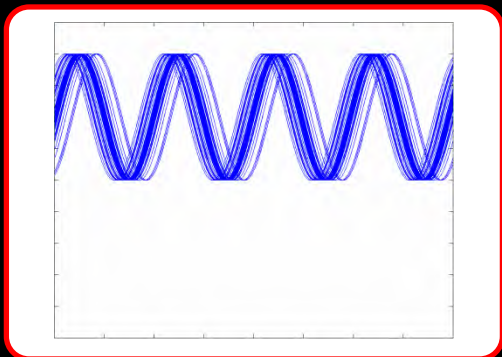
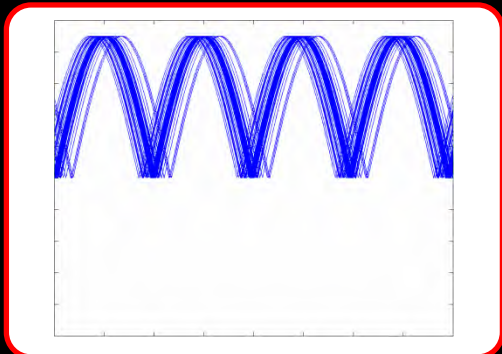
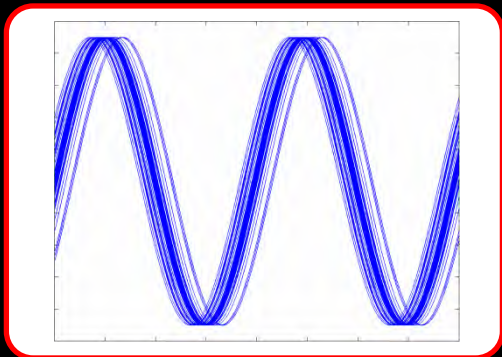
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- Phase Noise Intro – Additive and Absolute
- Oscillator Phase Noise Measurement Setup
- Theory
- PLL Basics for Phase Noise Measurements
- Baseband Measurements
- Calibration
- Taking the Measurements

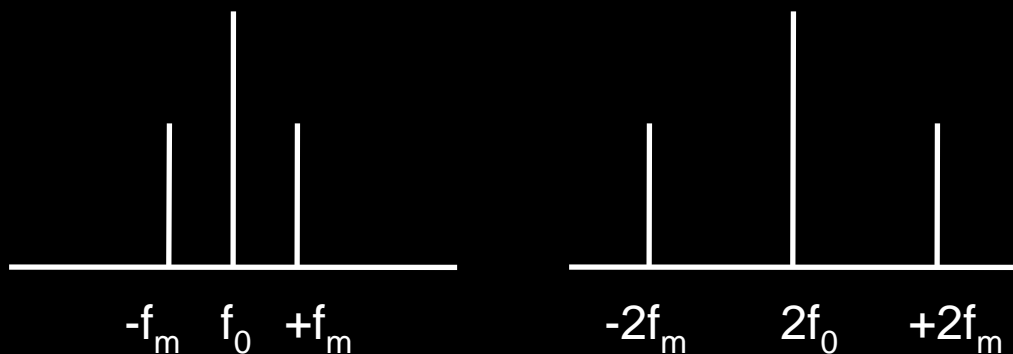
# Phase Noise is Related to Jitter



# Phase Noise & Freq Multiplication

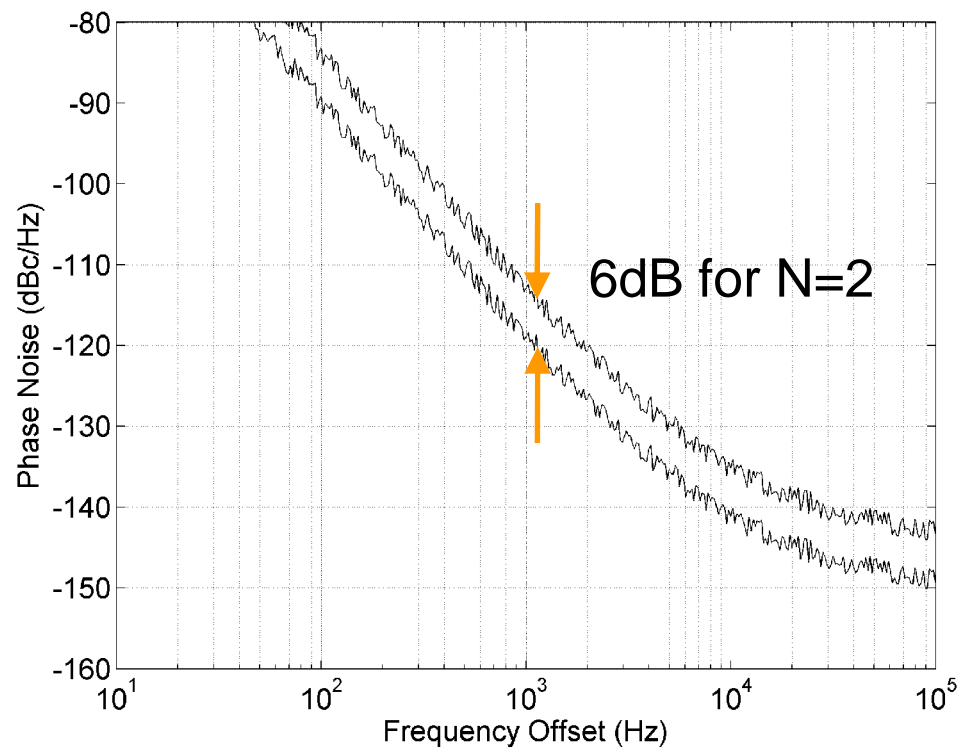


- Jitter remains CONSTANT through ideal Frequency Multiplication
- Phase Noise increases during Frequency Multiplication
- Phase Noise is relative to Carrier



$$\sin(\theta) \cdot \sin(\theta) = \frac{1}{2} - \frac{1}{2} \cos(2 \cdot \theta)$$

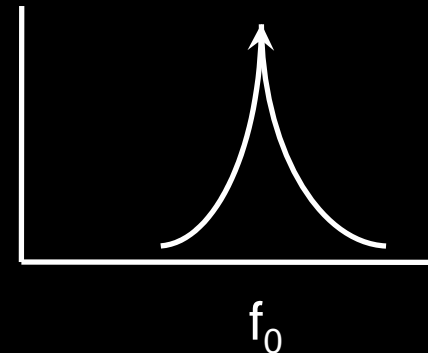
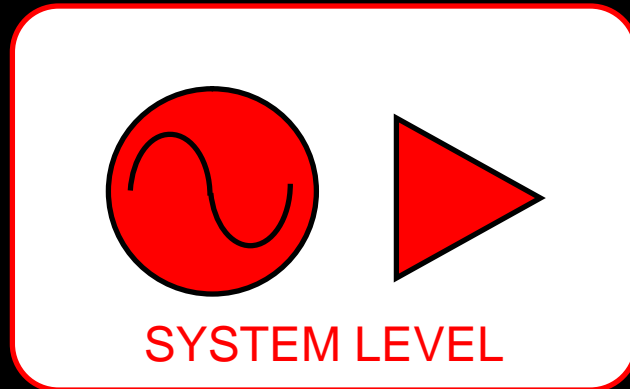
# Phase Noise & Freq Multiplication



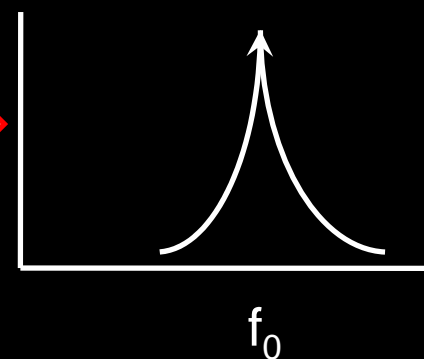
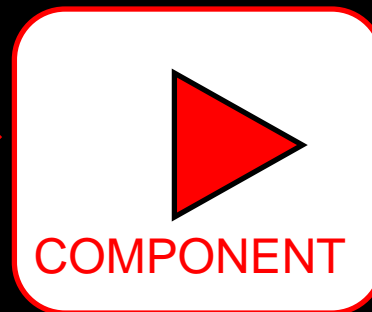
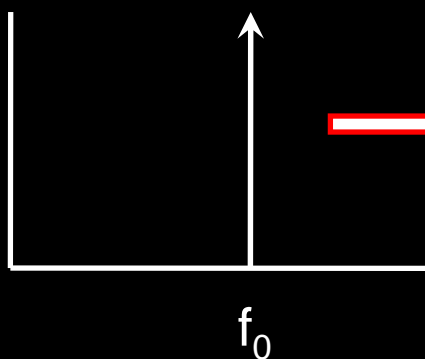
$$20 \cdot \log_{10} N$$

$N$  = Multiplication Factor

# Absolute vs. Additive (Residual)



ABSOLUTE



ADDITIVE  
(RESIDUAL)

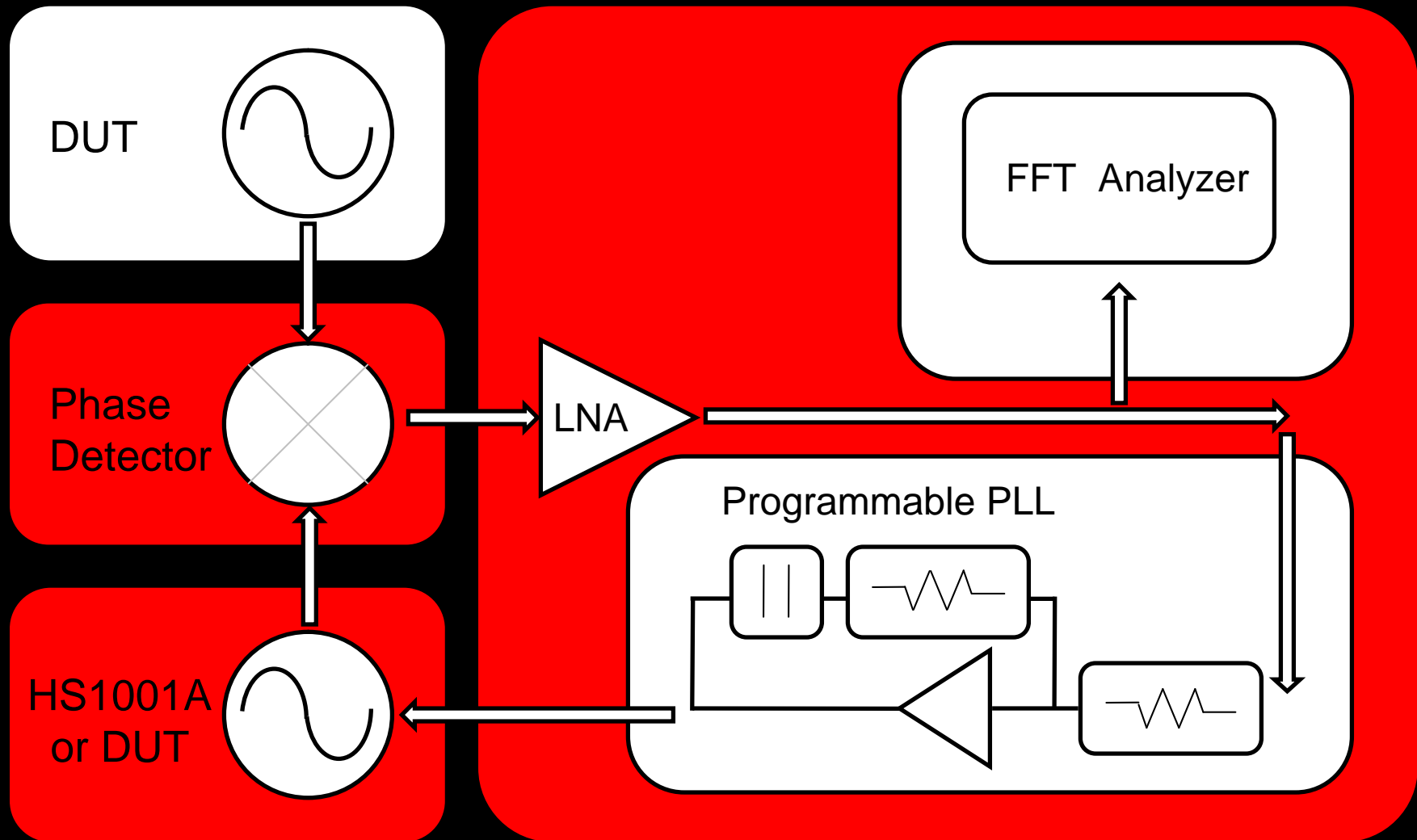
# Measurements vs. Cost

Components are available to build a Phase Noise Test System if engineering know-how and time is available.

There are specific Phase Noise Test instruments available for a high price tag.

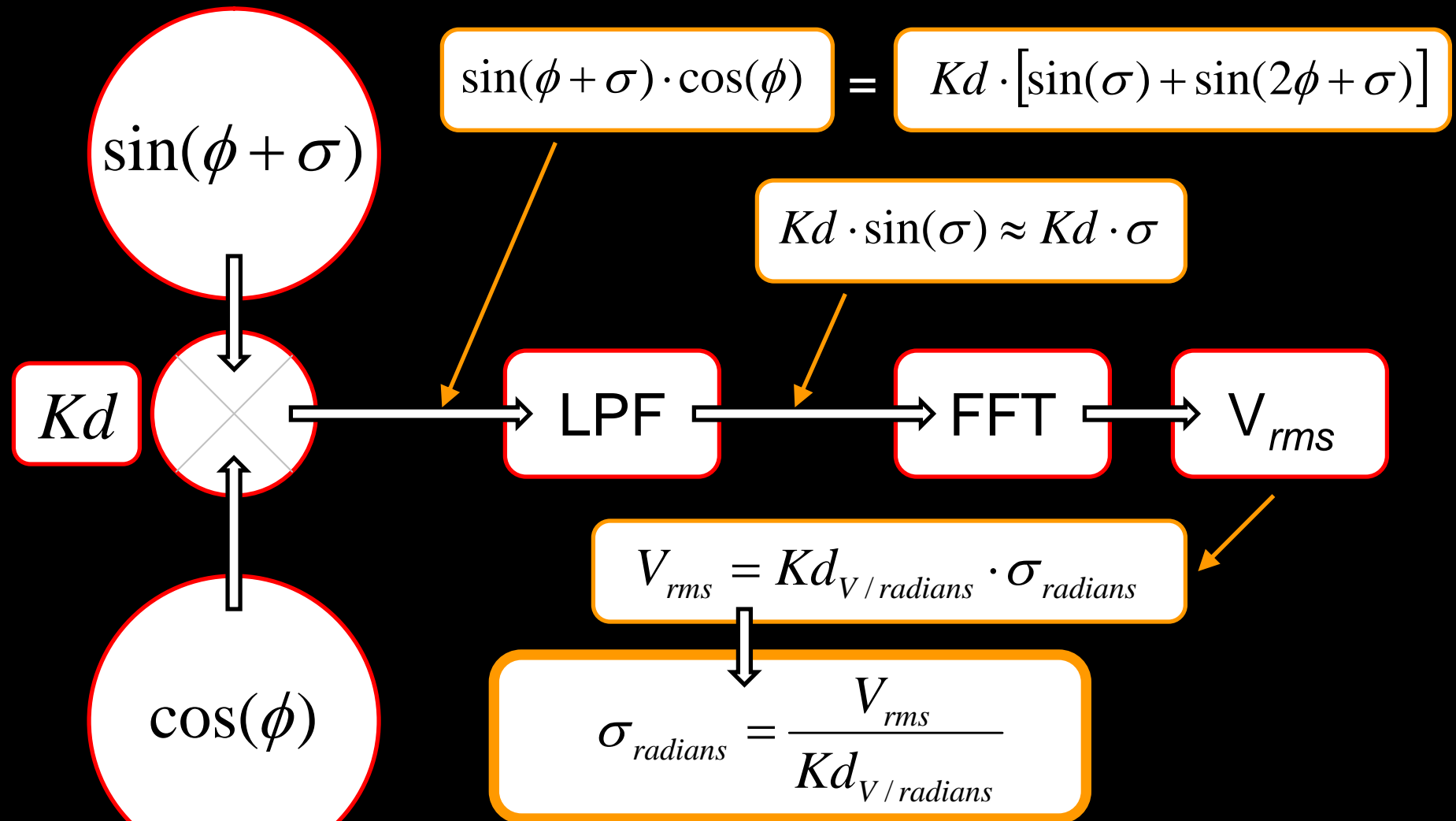
**HYBRID APPROACH:** Purchase appropriate, versatile test equipment and accessories as Phase Noise Test subsystems saving design, calibration and setup time.

# Hybrid Test System: 3 to 5 Devices





# Theory: Test System Summary

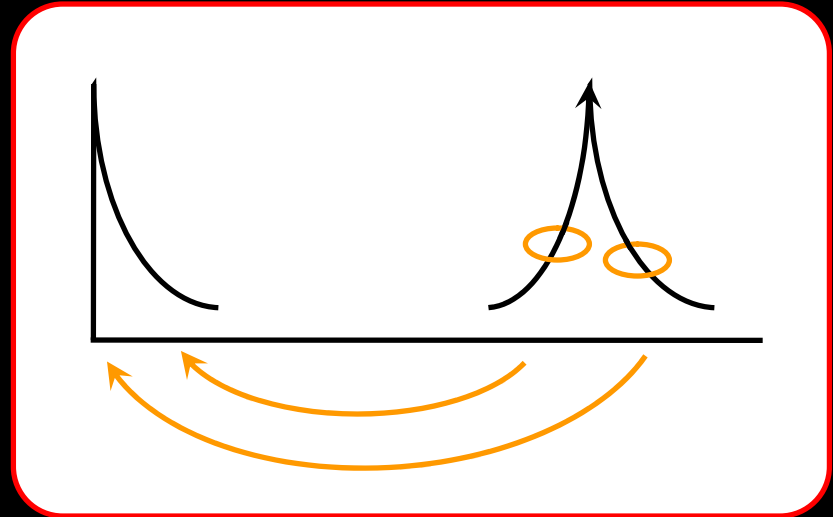


# Theory: DSB vs. SSB

$$\sigma_{DSB} = \sqrt{\sigma_{upper}^2 + \sigma_{lower}^2}$$

$$|\sigma_{upper}| = |\sigma_{lower}| = |\sigma_{SSB}|$$

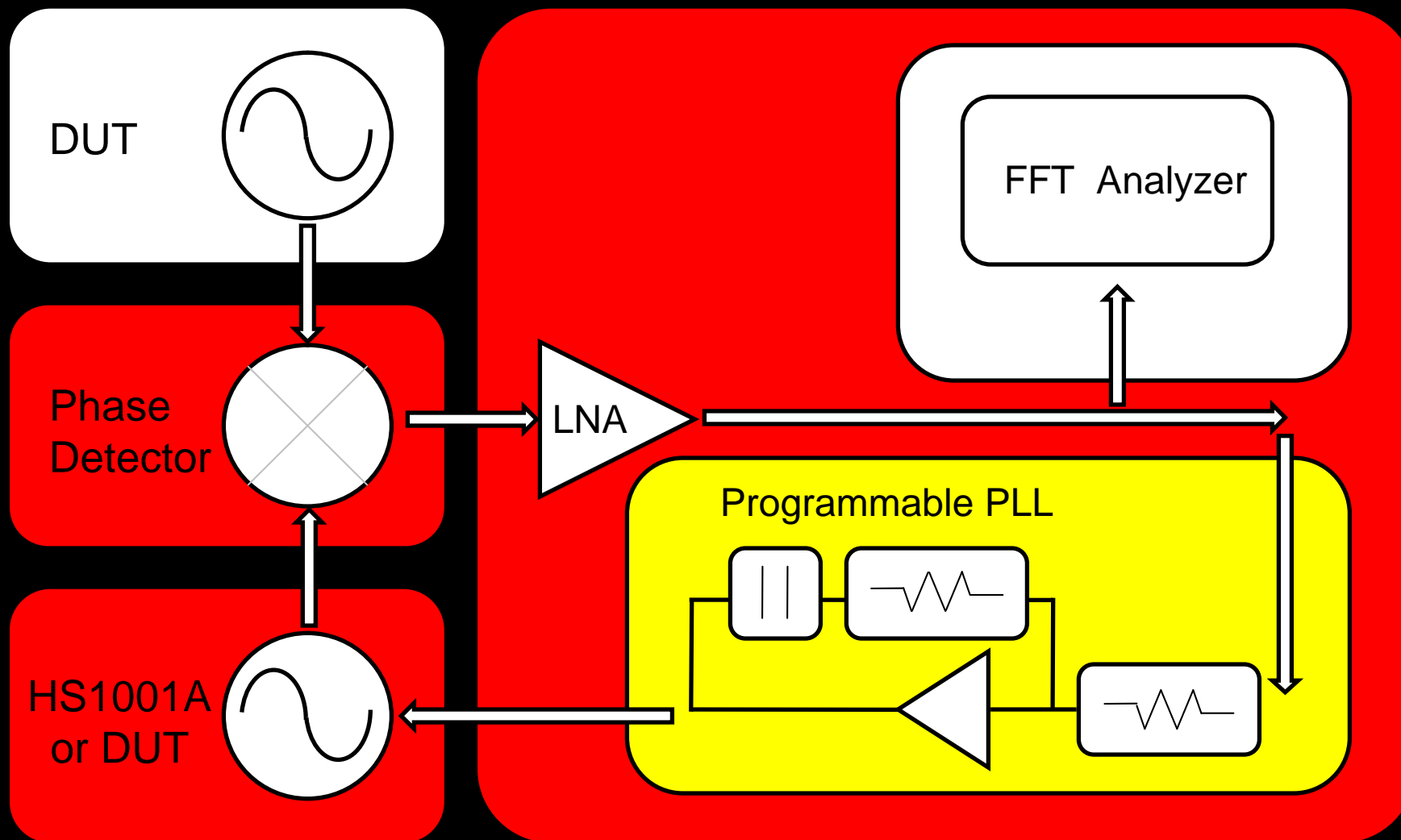
$$\sigma_{DSB} = \sqrt{2} \cdot \sigma_{SSB}$$



A Baseband Measurement is a  
**Double Sideband Measurement**

**NOTE: there is a 3dB Difference!**

# Measurement Setup: PLL

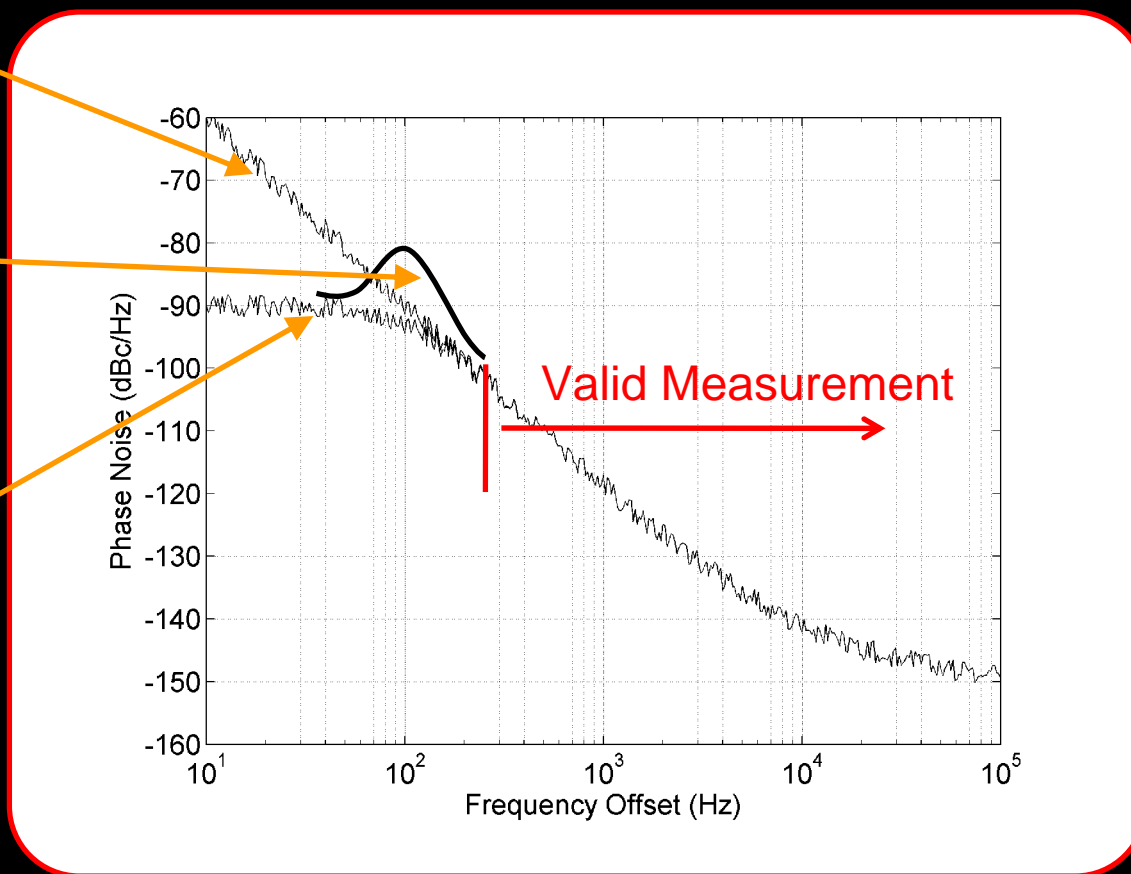


# Absolute Phase Noise: PLL

Unlocked  
Phase Noise

Damping Factor  
affects the  
Loop Transition

PLL Locked  
Bandwidth

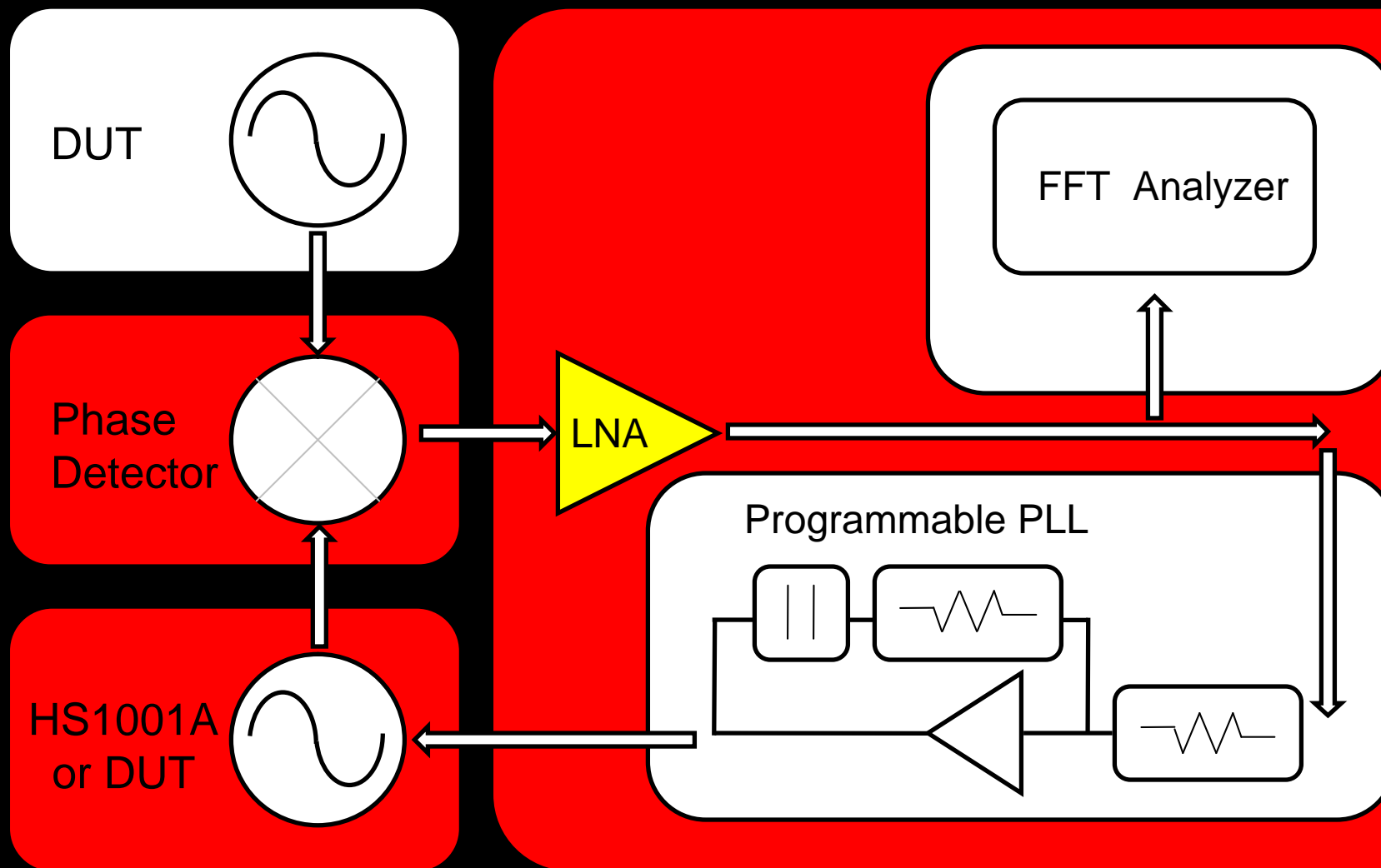


# PLLs for Phase Noise Measurements

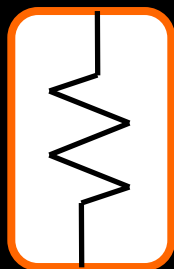
Phase Locked Loops are used for locking two oscillators together, making their phase noise coherent

Within the lock bandwidth: the phase noise measurements are NOT valid without an accurate knowledge of the PLL loop

# Measurement Setup: LNA



# Resistor Equivalent Voltage Noise



$$N_{thermal} = \sqrt{4kTBR}$$

$$50\Omega = 0.91nV / \sqrt{Hz}$$

$$500\Omega = 2.87nV / \sqrt{Hz}$$

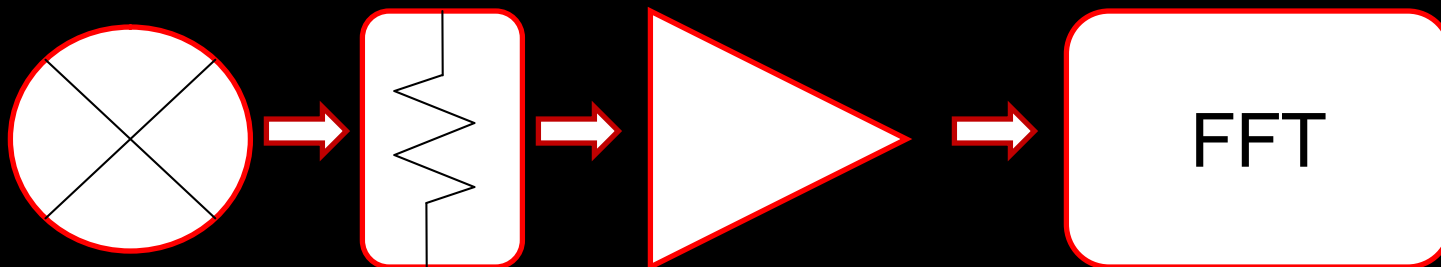
$$5k\Omega = 9.10nV / \sqrt{Hz}$$

$$\text{Signal To Noise Ratio} = V_{rms} / V_{thermal}$$

# Baseband Low Noise Amplifier

$$50\Omega = 0.91nV / \sqrt{Hz}$$

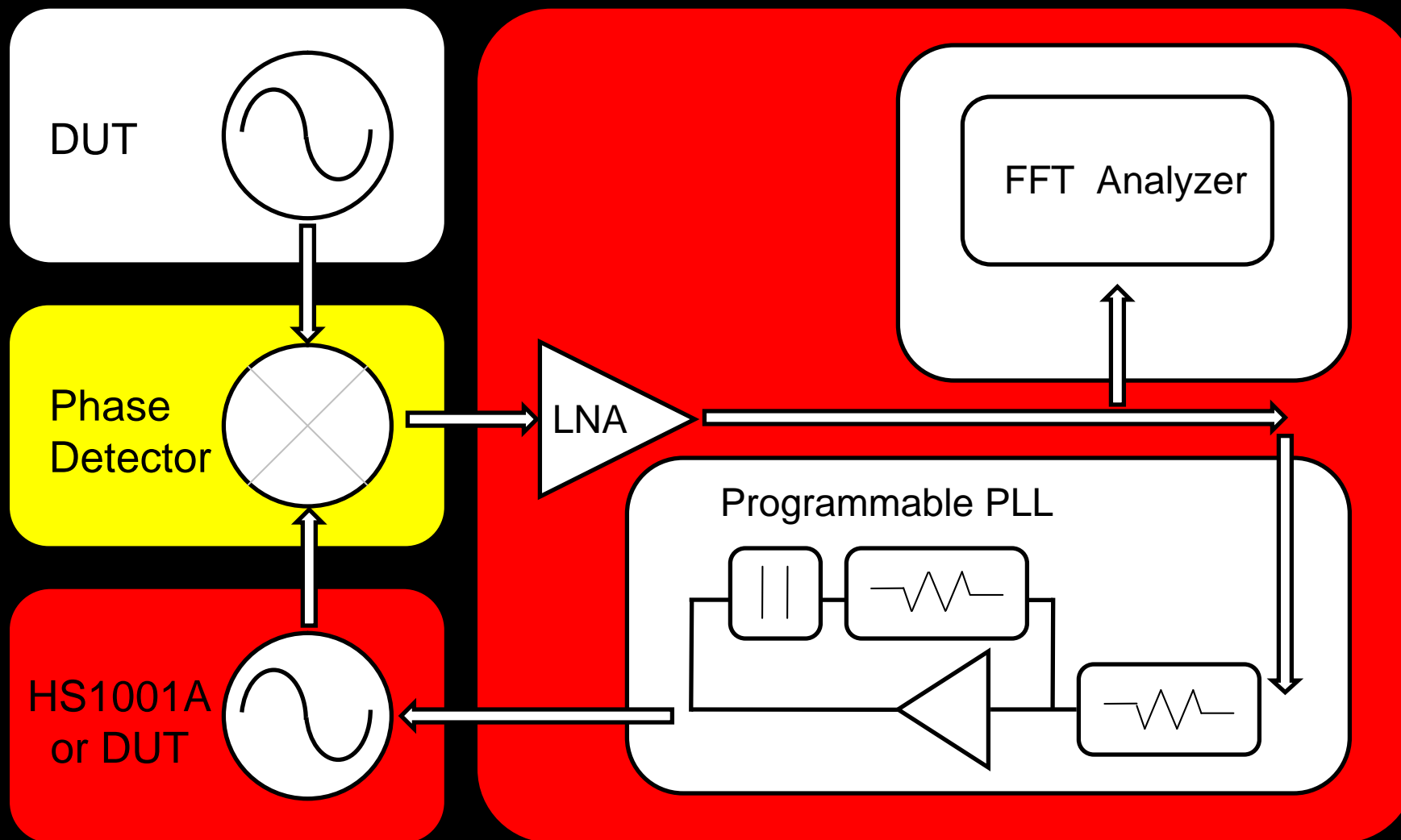
$$LNA \approx 1.0nV / \sqrt{Hz}$$



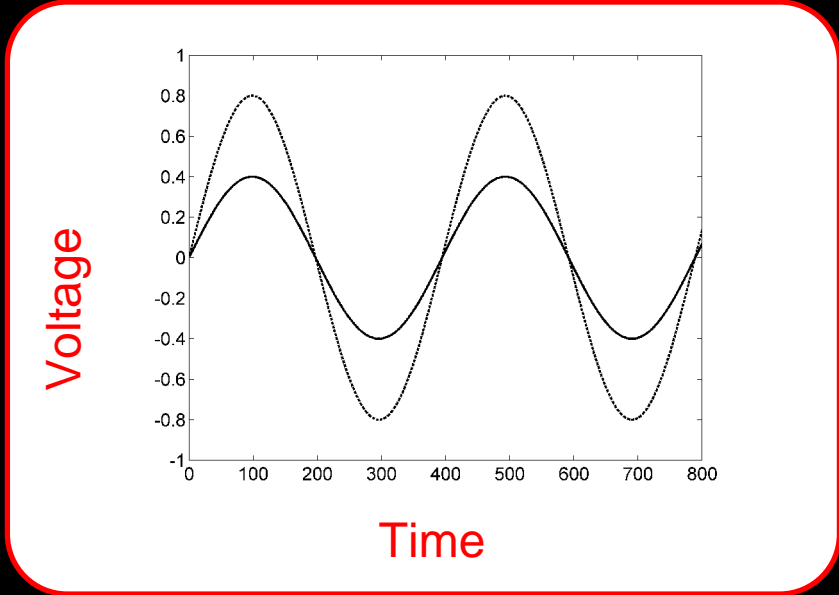
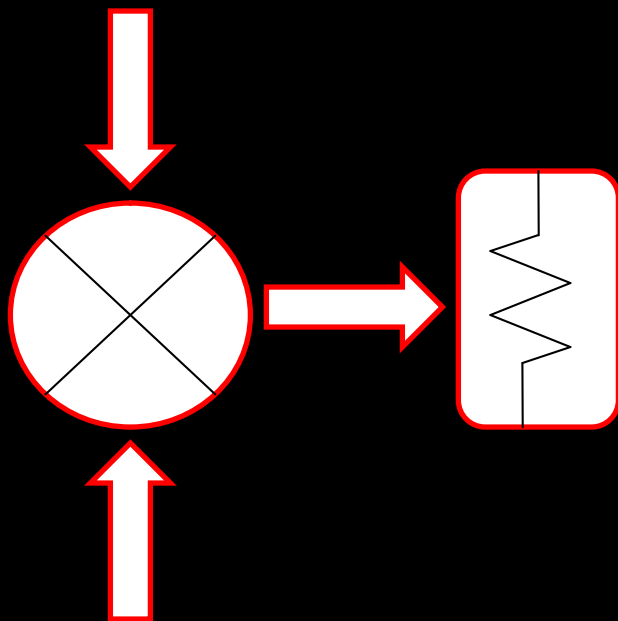
$$N_{system} = \sqrt{0.91nV^2 + 1.0nV^2} = 1.35nV / \sqrt{Hz} = -177.4dBV / \sqrt{Hz}$$



# Measurement Setup: Phase Detector



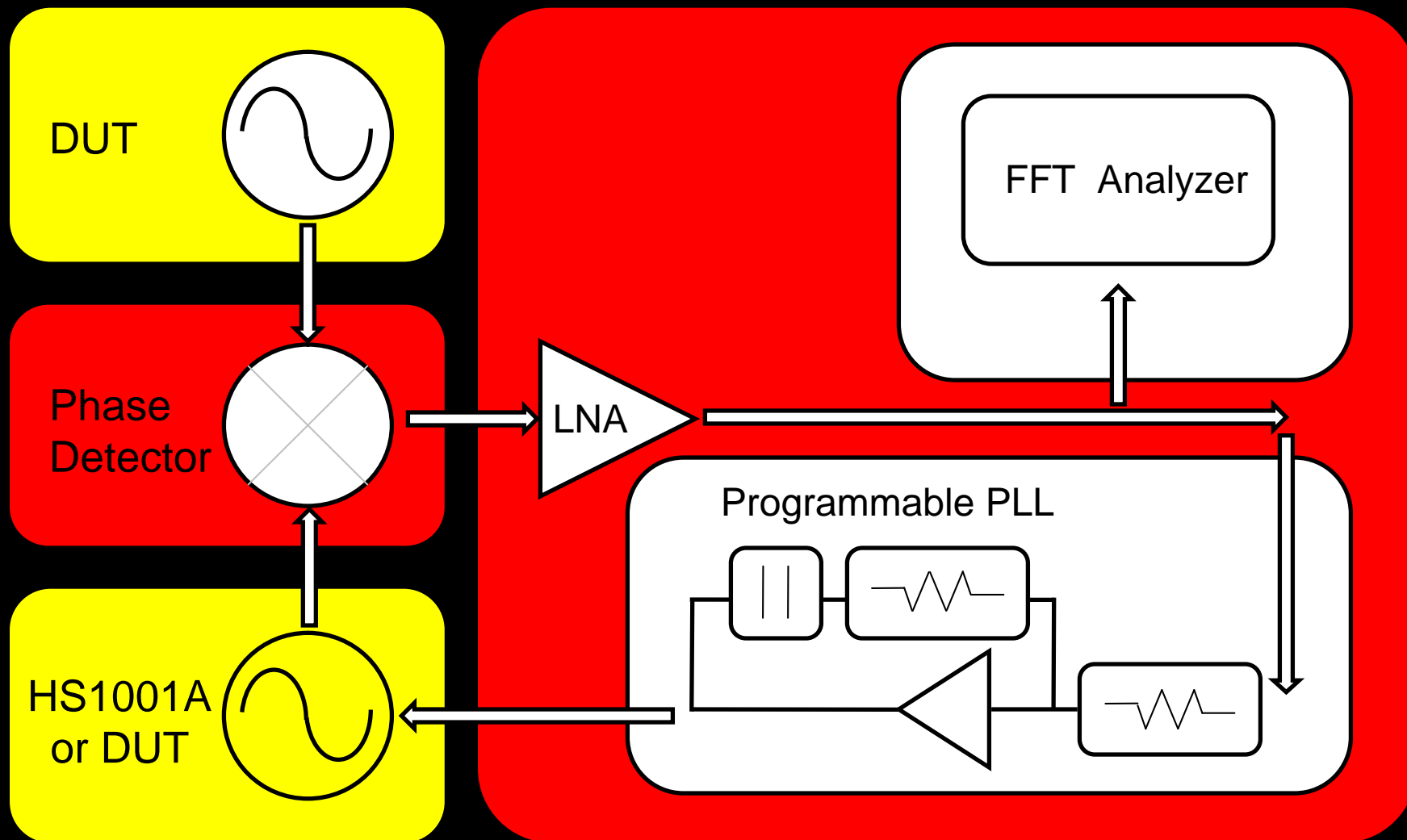
# Mixers as Phase Detectors



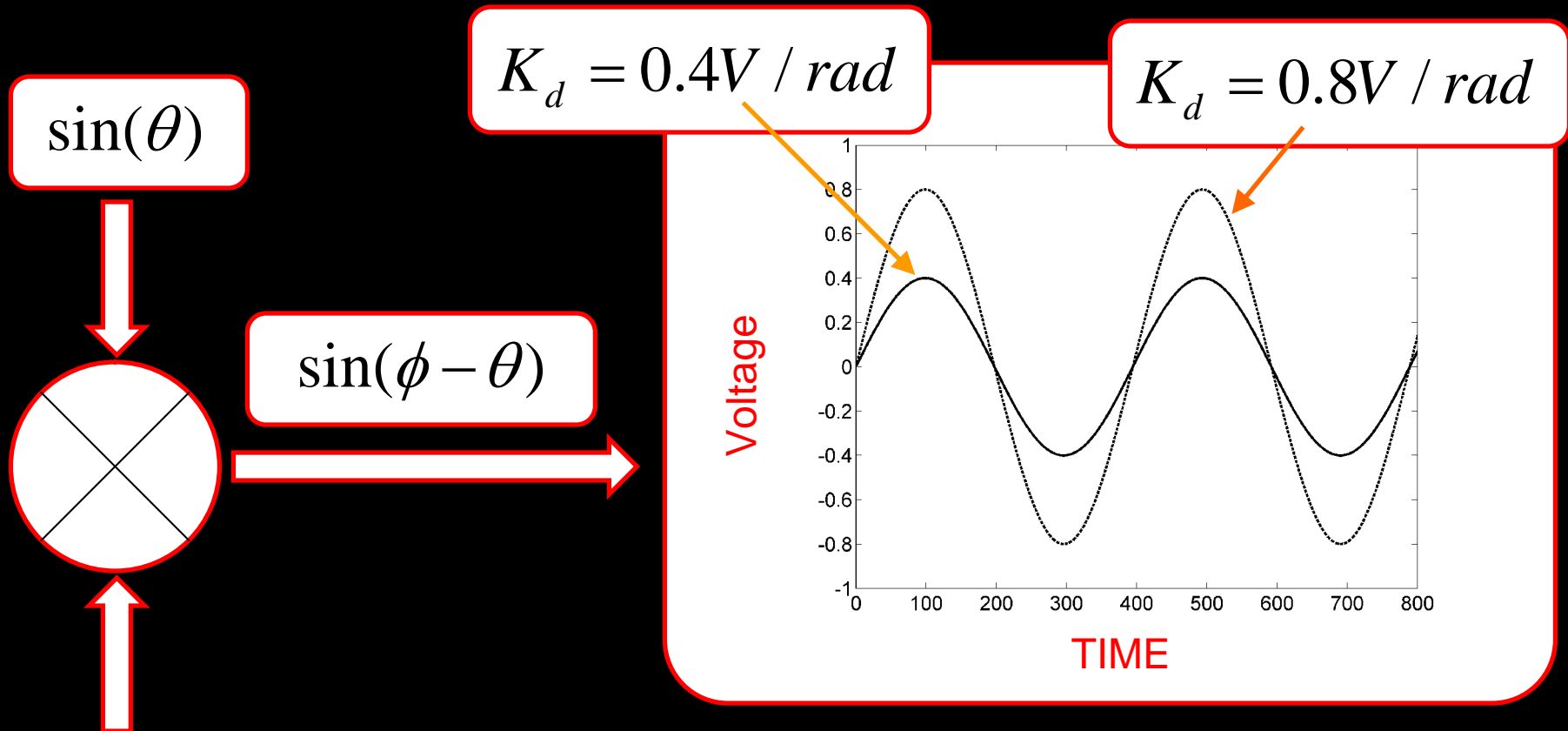
$$V_{rms} [dB]_{50\Omega} = -11dBV$$
$$V_{noise} [dB]_{50\Omega} = -177.5dBV$$
$$SNR = -166.5dBc$$

$$V_{rms} [dB]_{500\Omega} = -5dBV$$
$$V_{noise} [dB]_{500\Omega} = -170.8dBV$$
$$SNR = -165.8dBc$$

# Measurement Setup: Phase Locking



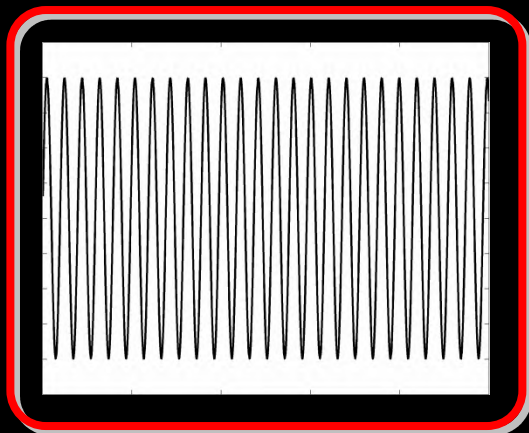
# Test System Calibration



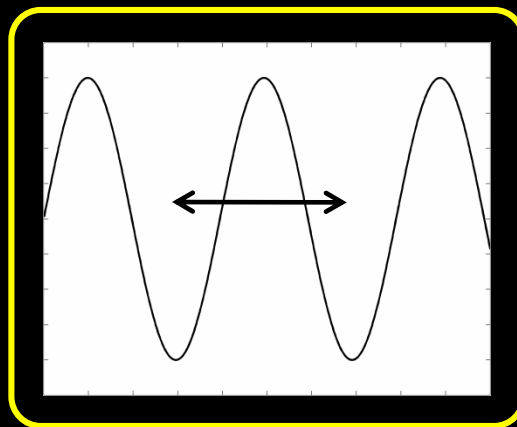
**Calculate the Slope of the Zero Crossing:**  
Sinusoidal : the derivative of the beat frequency  
In other words... the peak voltage =  $K_d$ !!

# Taking the Measurement: Locking

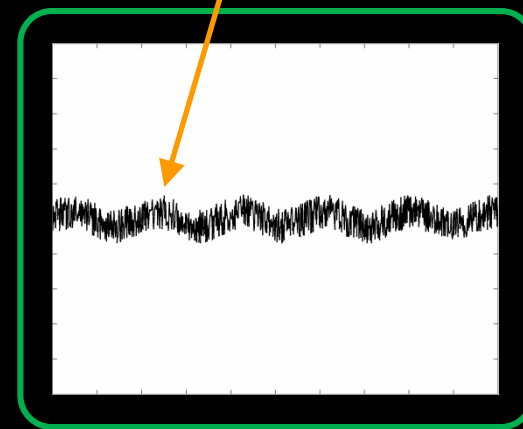
Unlocked



Beat Frequency decreases as synthesizer closes in on the DUT frequency



Spurs (60Hz) are observed as a small sinusoid



When the Synthesizer frequency is near the DUT frequency and within the lock bandwidth **they will lock together**

# Taking the Measurement: FFT

Measurement Duration  $\sim 10x$  ( $1/$  lowest frequency)

A 10Hz to 100kHz measurement will take  $\sim 1-2$  seconds

Freq

110MHz

Kd

0.4

Preamp  
Gain

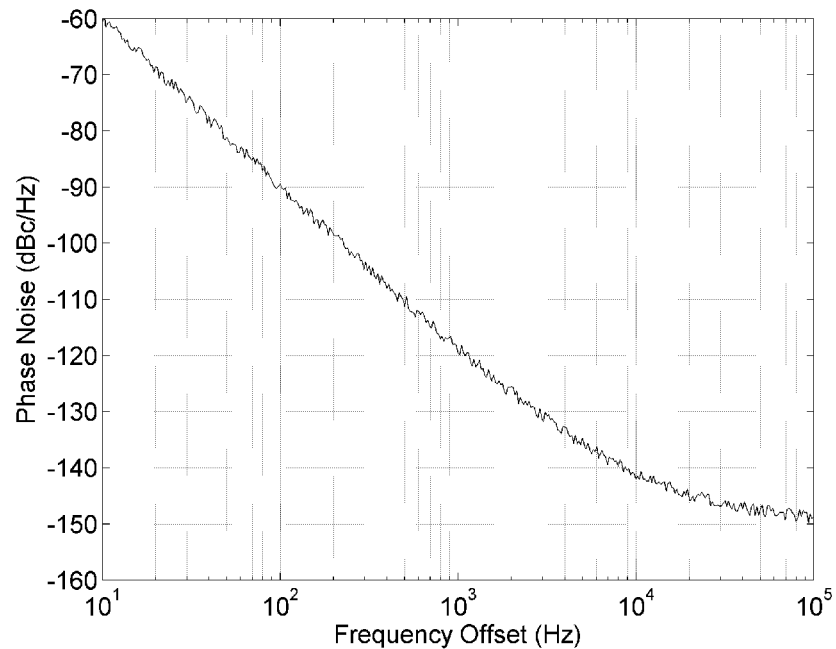
60dB

PLL BW

100Hz

PLL  
Damping  
Factor

1.5



# Test System Cost Summary

## I. HYBRID TEST SYSTEM:

- 2 instruments:
  1. Tunable, Ultra Low Phase Noise Source
  2. FFT Analyzer with integrated PLL
- Total Price: typically \$6,500 to \$8,500 (US)
- Fast setup with Accurate Measurements

## II. Discrete Components Test System

- Component Count: approx 30 components MINIMUM
- Total Price: typically \$10,000 to \$50,000 (US)
- Slow setup time and component phase noise verification

## III. Dedicated Phase Noise Test System

- Total Price: typically > \$60,000 (US)
- Fast Setup, but with High Cost of Ownership

# THANK YOU

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